

Notice of References Cited

Application/Control No.

10/079,389

Applicant(s)/Patent Under
Reexamination
BOWLEY ET AL.

Examiner

Hal D Wachsman

Art Unit

2857

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,976,740	11-1999	Ausschnitt et al.	430/30
	B	US-5,969,273	10-1999	Archie et al.	73/865.8
	C	US-6,509,952	01-2003	Govil et al.	355/52
	D	US-5,750,294	05-1998	Hasegawa et al.	430/22
	E	US-2003/0048458	03-2003	Mieher et al.	356/601
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Su et al., "Sidewall angle measurements using CD SEM", 23-25 September 1998, IEEE, Advanced Semiconductor Manufacturing Conference and Workshop, pages 259-261.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.